


<b>Search Notes</b>  	<b>Application/Control No.</b>  10575165	<b>Applicant(s)/Patent Under Reexamination</b>  VION, PATRICK
	<b>Examiner</b>  Christopher S Kim	<b>Art Unit</b>  3752

SEARCHED			
Class	Subclass	Date	Examiner
239	504, 499, 427, 370, 590.3, 590.5	4/12/08	CK

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner